Structured Electronic Design

Intrinsic CS stage: Stationay noise model

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CS stage stationary noise behavior

 $f_{max} = 2.0e+09$ $f_{max} = 4.0e+09$ $f_{max} = 6.0e+09$ $f_{max} = 8.0e+09$ $f_{max} = 1.0e+10$

25

50

3.0

2.5

[gp] <u>4</u> 1.5

1.0

0.5

(4)

Circuit Data



A1 Include library

SLiCAP.lib

A2 Parameter definitions .param R_s=600 W=54.6u L=180n ID=6.15m IG=C Study noise behavior for various source types

100

W [um]

75

Netlist: CS stage resistive noise



 $f_T = 3.577\,10^{10}$

- Find design parameters and show stopper values









 i_d [A] noise current associated with the drain current

$$S_{i_d} = 4kTn\Gamma g_m \left(1 + \frac{f_\ell}{f}\right) \left[\mathbf{A}^2 \mathbf{F}\right]$$

 Hz^{-1}



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 $\Gamma = \frac{1}{2} \left[- \right]$ in weak inversion

- Hz^{-1}



$$S_{i_d} = 4kTn\Gamma g_m \left(1 + \frac{f_\ell}{f}\right) \left[A^2 H\right]$$
$$\Gamma = \frac{1}{2} \left[-\right] \text{ in weak inverse}$$
$$\Gamma = \frac{2}{3} \left[-\right] \text{ in strong inverse}$$

- Hz^{-1}
- sion
- rsion



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$$\Gamma = \frac{2}{3} \left[-\right] \text{ in strong inverse}$$
$$\Gamma = \frac{\frac{1}{2} + \frac{2}{3}IC}{1 + IC} \left[-\right]$$

- Hz^{-1}
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- ersion



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$$f_\ell = KF \frac{3\pi}{4kTn\Gamma} f_T \left[\text{Hz}\right] \text{ comparison}$$

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orner frequency 1/f noise



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 $\operatorname{KF}[J]$ process parameter

- Hz^{-1}
- sion
- ersion

orner frequency 1/f noise



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$$f_\ell = KF \frac{3\pi}{4kTn\Gamma} f_T \left[\text{Hz}\right] \text{ common }$$

$$KF \left[\text{J}\right] \text{ process paralised}$$

$$f_\ell \propto f_T$$

- Hz^{-1}
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 I_G [A] DC gate current





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 f_{ℓ_g} [Hz] corner frequency 1/f gate current noise



 $i_q [A]$ noise current associated with the gate current

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 $I_G[A]$ DC gate current

 f_{ℓ_q} [Hz] corner frequency 1/f gate current noise

Often the gate current is assumed zero and this noise source is ignored



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